

# *Magnetic Flux Invasion and Field-Capturing in Pulsed-Field Magnetization for Layered $\text{MgB}_2$ Bulk Magnets*

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# MgB<sub>2</sub>

➤  $T_c = 39\text{ K}$

→ the highest among metallic compounds

➤ **No weak links among crystal grains**

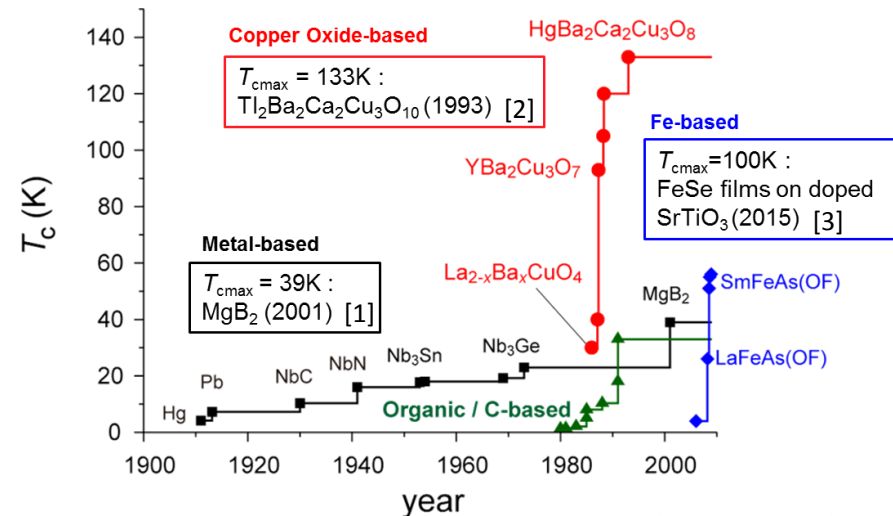
→ no needs for crystal grain alignment

➤ **Pinning centers reside at grain boundaries**

→ fine particle size results in high  $J_c$  values

➤ **Easy to produce for near-net shapes**

→ feasible practical application to such as  
NMR, DDS etc.



[1] Nagamatsu. J *et al.*, *Nature* 410 (2001) 63

[2] A. Schilling, *et al.*, *Nature*, vol. 363, pp. 56-58, 1993

[3] J-F. Ge. *et al.*, *Nature Materials*, vol. 14, pp. 285-289, 2015

[4] M. Kambara *et al.*, *Supercond. Sci. Technol.* 14 (2001) L5

[5] D.C. Larbalestier *et al.*, *Nature* 410 (2001) 186

[6] P Mikheenko *et al.*, *Supercond. Sci. Technol.* 20 (2007) S264–S270

# Fabrication of samples

## Sample preparation

Leibniz-Institut für Festkörper - und  
Werkstoffforschung Dresden (IFW Dresden)



Dr. Wolfgang Häßler,  
Ms. Juliane Scheiter

## Ball-milled mixture of Mg and B powders

➤ 250 rpm x 10 h

## Hot pressing was operated

➤ under pressure of 480 MPa  
temperature 700 C  
time 10 min

COMPOSITION AND DIMENSIONS OF  $\text{MgB}_2$  BULK SAMPLES

Sample No.	MH1	MH2	MH3	MH4	MH5	MH6	MH7	MH8
Composition	Un-doped	Un-doped	Un-doped	Un-doped	Un-doped	SiC 3%	SiC 3%	SiC 3%
Thickness $t$ (mm)	1.12	1.10	1.13	1.37	1.36	3.30	3.34	6.58

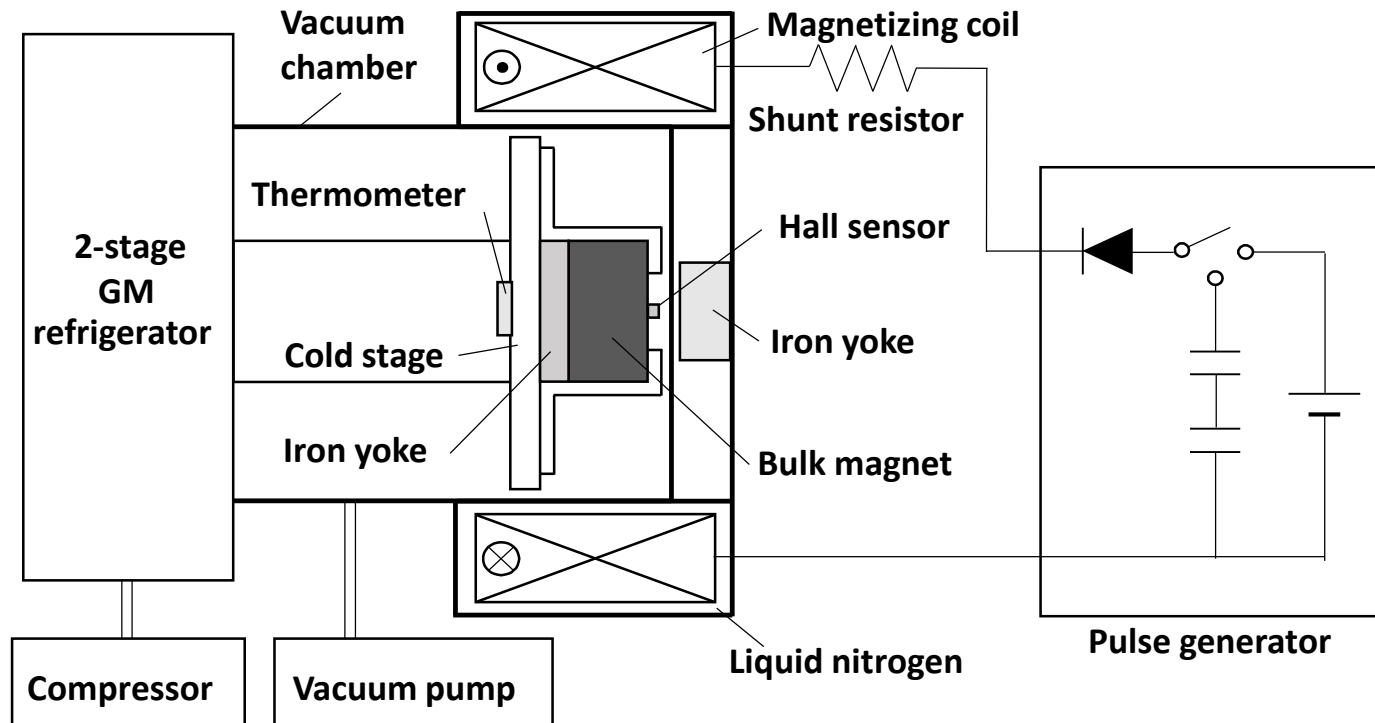
All samples are 20 mm in diameter

< Magnesium powder >  
Goodfellow, purity 99.8 %,  
grain size < 250  $\mu\text{m}$

< Boron powder >  
PAVEZYUM, purity 98.5 %,  
grain size < 250  $\mu\text{m}$

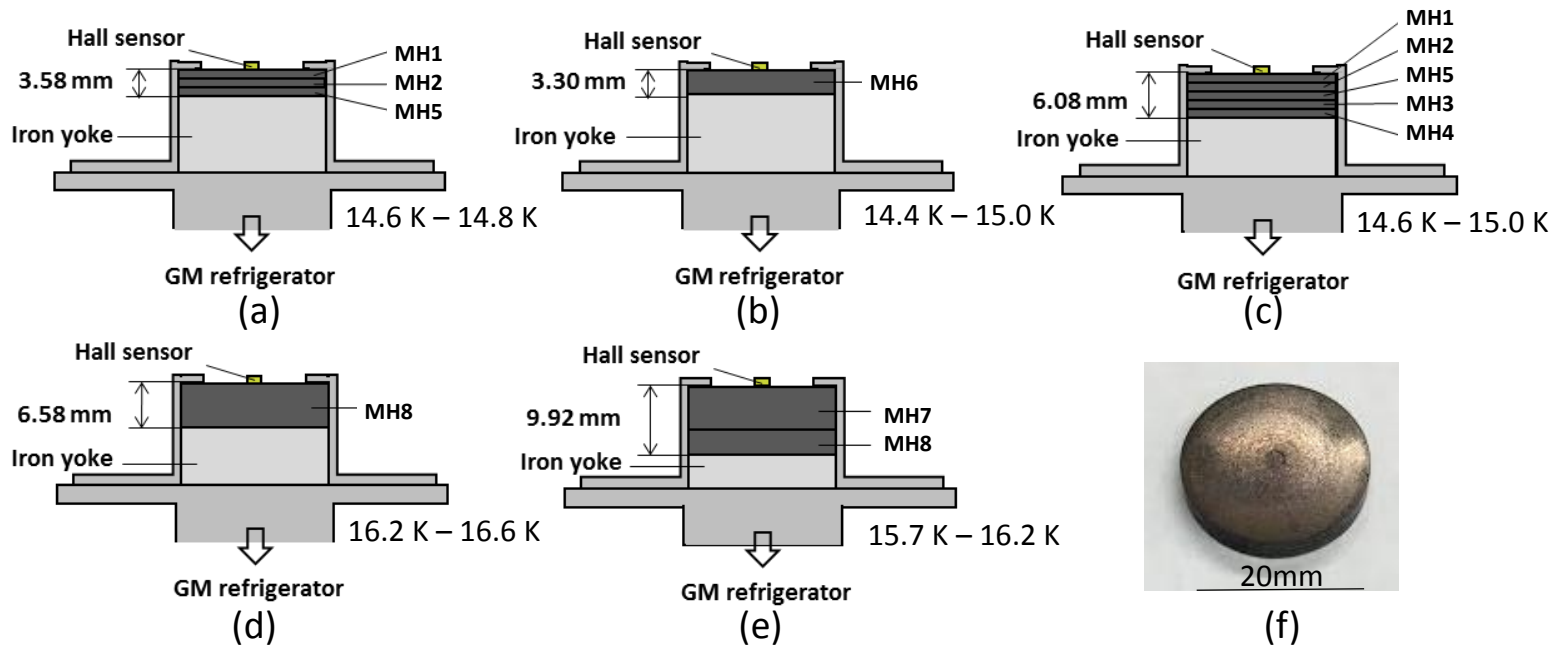
< SiC powder >  
Alfa Aesar, purity 95.0 %,  
grain size < 30 nm

# Schematic drawing of experimental setup for PFM



- The temperature reached about 14.4-16.6 K
- Thermometer is attached at the cold stage
- A pair of iron yokes are attached close to the both side on the sample

# Sample arrangements on the cold stage



➤ **Applied field  $B_a$**

0.4 T – 2.0 T

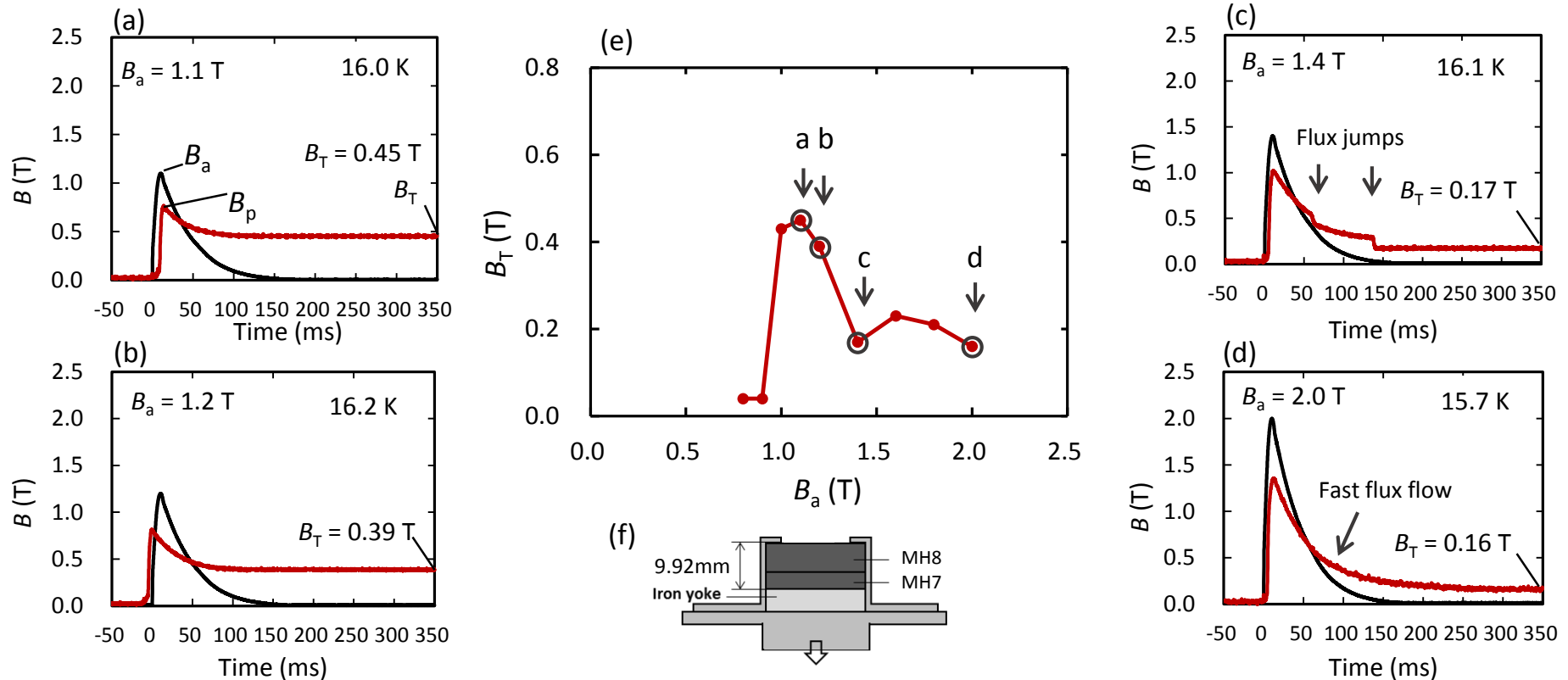
➤ **Magnetizing coil**

112 Turns (Copper winding)

Outside/inside diameter : 114/83

- Operating temperature measured at the cold stage before each PFM shot

# Trapped field $B_T$ and evolitional profiles during PFM



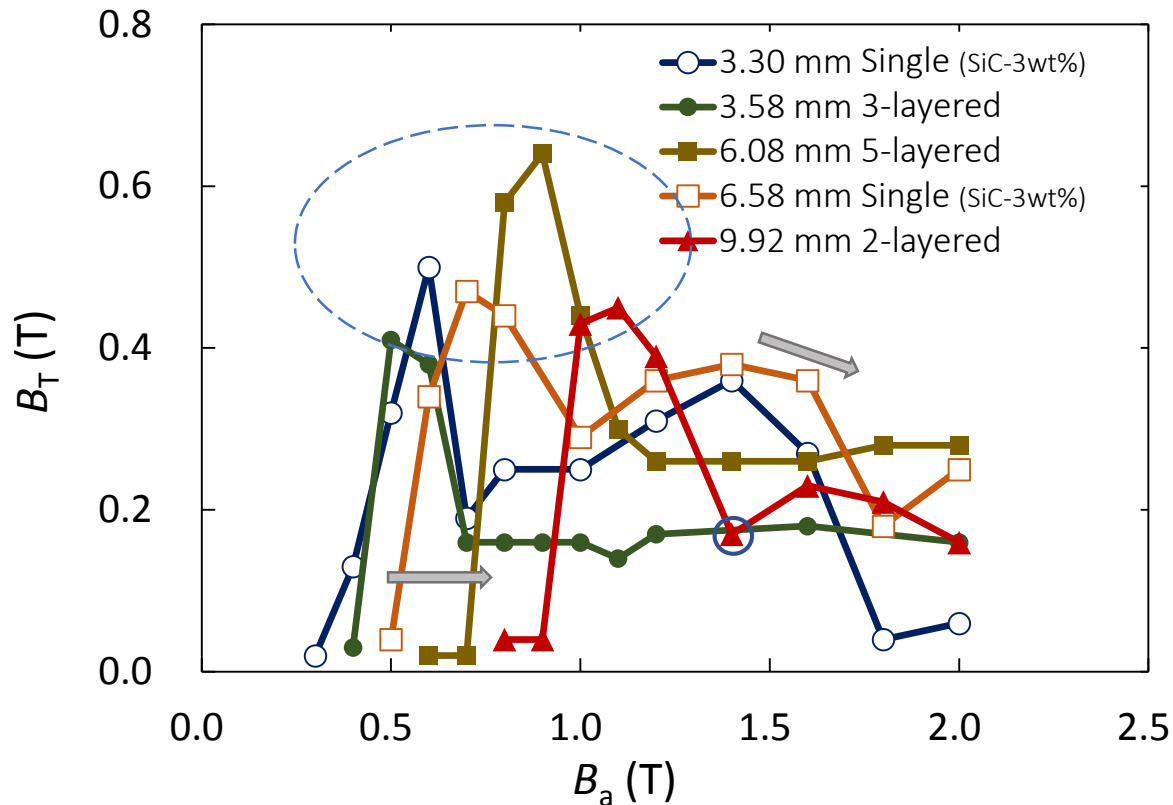
$B_a$ : Maximum applied field calculated by the pulsed current

$B_p$ : Penetration field at the highest peak measured at the top surface during PFM

$B_T$ : Trapped field after PFM

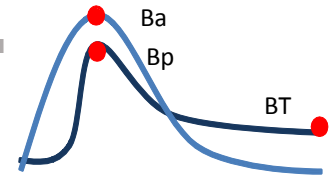
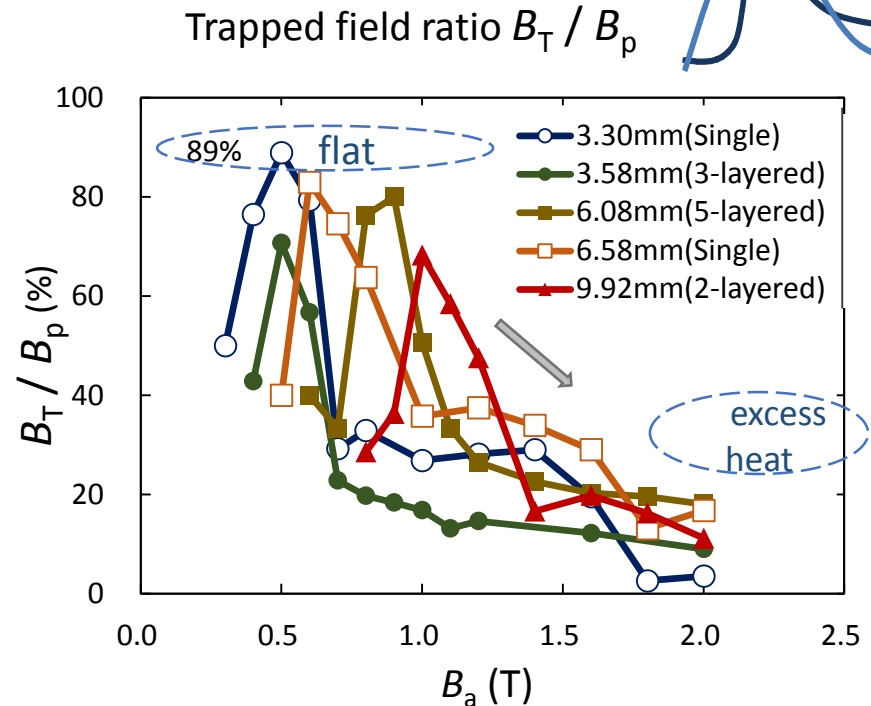
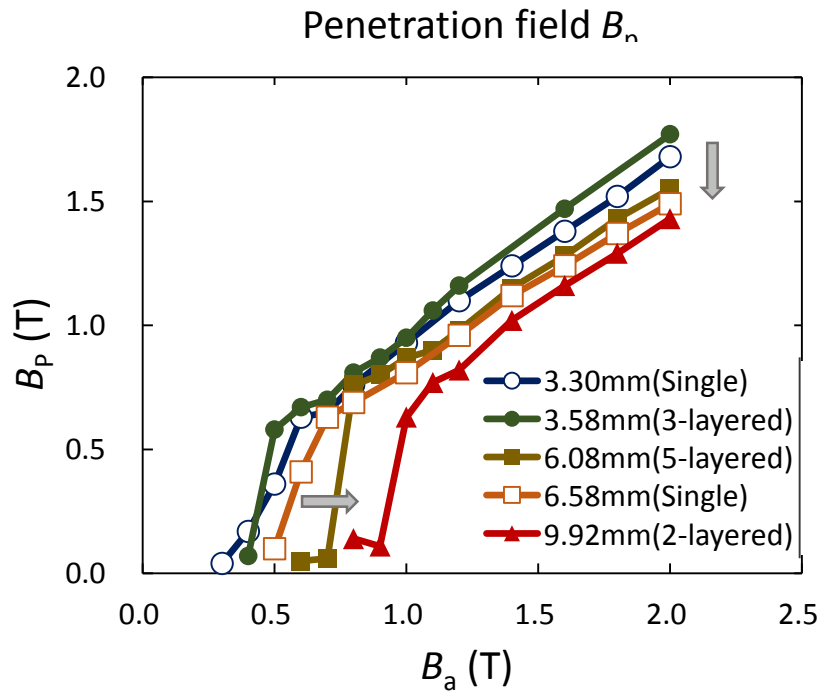
- The trapped field reached 0.45 T
- The flux jumps and fast flux flows were observed in high field application over 1.4 T

# Trapped Fields measured with various sizes in thickness



- The thicker the sample, the higher field required for flux invasion start  
→ Enhanced shielding effect with size in thickness
- The samples showed the same  $B_a$  values 0.4-0.64 T  
→ the sample in the critical state with the relevant  $J_c$  values
- Frequent flux jump (O) and fast flux flow → Low specific heat, weak pinning

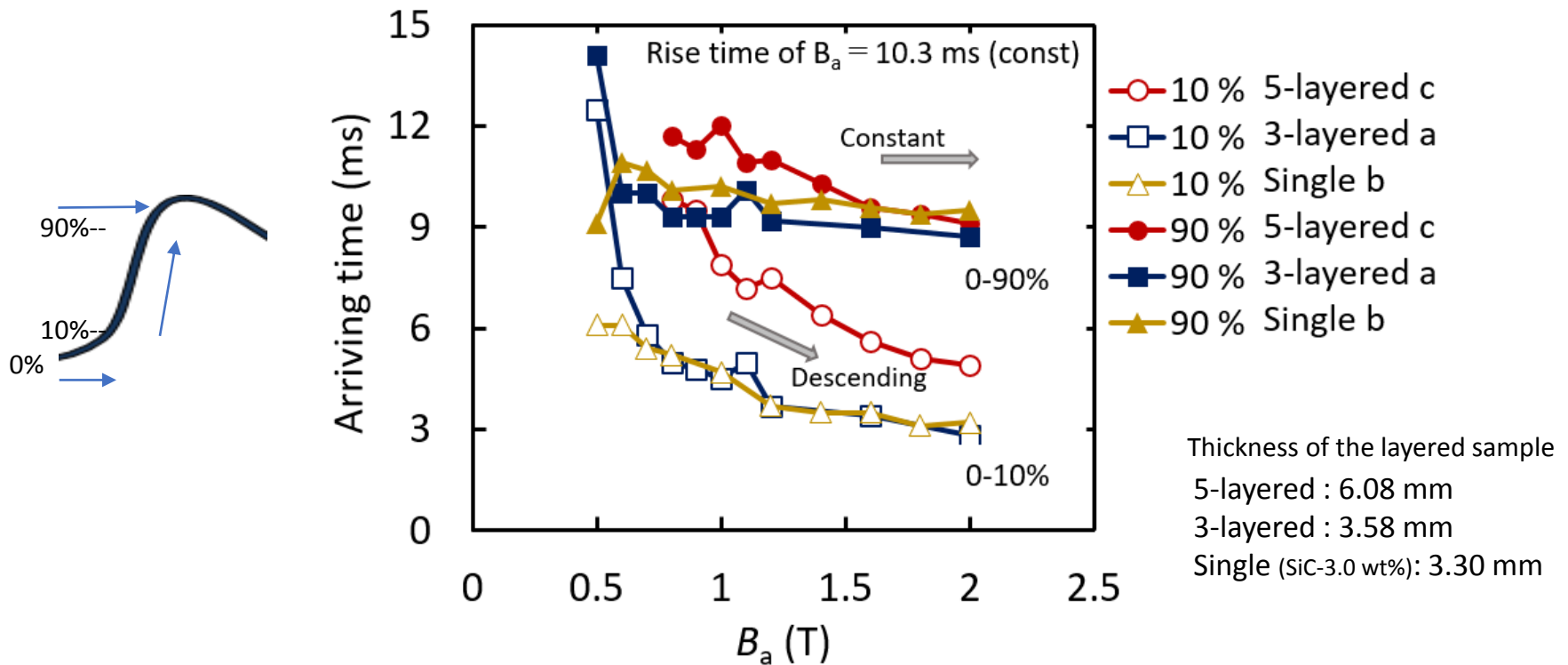
# Applied field dependence of penetration fields and ratios of trapped field $B_T$ / penetration field $B_p$ with various sample thickness



- The field invasion tends to be suppressed with increasing thickness
- $B_T$  degrades with thickness  $\rightarrow$  The shielding effect were promoted with thickness
- The ratios tend to descend  $\rightarrow$  The temperature rises enhanced with thickness



# Applied field dependence on the arriving time to the center from 0 to 10% and 90% of penetration field $B_p$ as a function of sample thickness



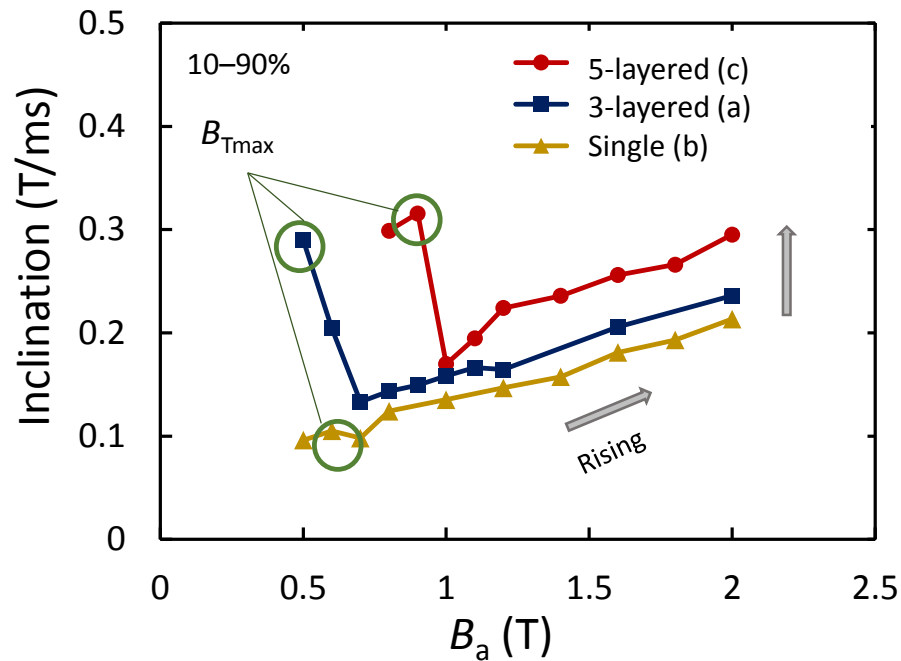
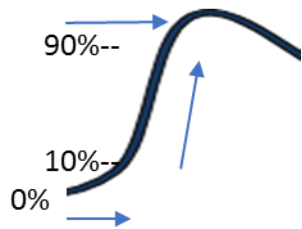
At the beginning, 0-10 % → The thicker, the longer the arriving time, due to the shielding effect, beside the flux starts to invade earlier with increasing applied field

Near the peak, 0-90 % → Almost constant arriving times as 8.7 – 9.5 ms, which means the flux-increasing speed become fast with increasing of applied field

→ The flux jumping into the sample is promoted with applied field strength

# Applied field dependence of field inclination in the range from 10 to 90% of penetration fields

=Flux increasing speed at 10-90%



For three sample thickness

Total thickness of the samples

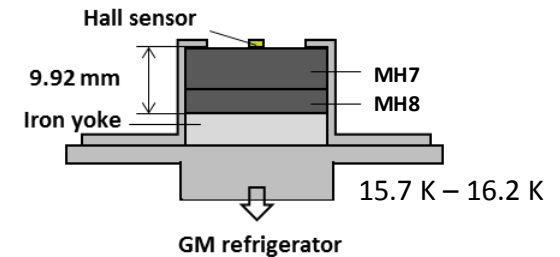
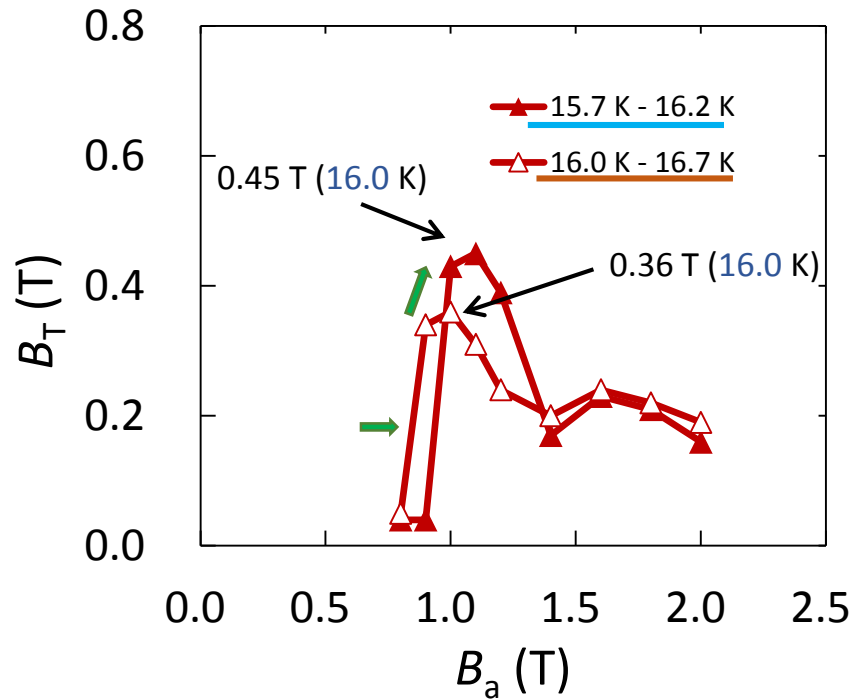
5-layered : 6.08 mm

3-layered : 3.58 mm

Single (SiC-3.0 wt% 2) : 3.30 mm

- Flux increasing speed tends to rise with increasing  $B_a$ , which rise with thickness
- Rapid invasion in low fields leads to high field capture of  $B_{Tmax}$

# Temperature dependence of flux invasion and trapped fields

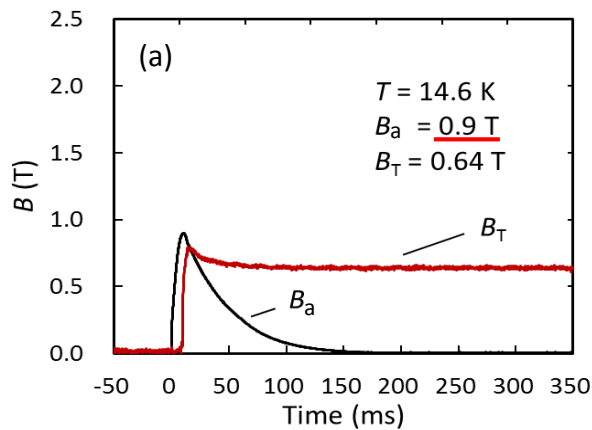


Temperature dependence  
→ Enhanced shielding effect  
and field capturing

# Conclusion

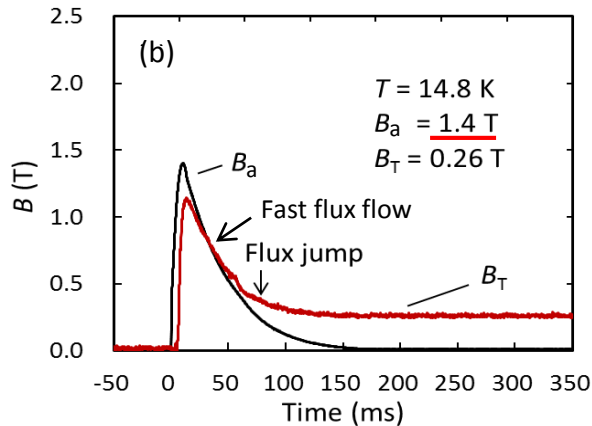
- The trapped field  $B_T$  reached 0.64 T in the narrow region of around 1 T in  $B_a$  with the least heat generation
- The "fast flux flow" and flux jumping occur in the region over 1.2 T, which caused significant drops in  $B_T$
- The flux invasion behavior strongly depends on the sample thickness, which mean that the flux invasion from the side surface of the samples
- The temperature rise caused by the flux motion due to the low specific heat should be responsible for low field-capturing

# Field Invasion Profiles (5-layered sample)

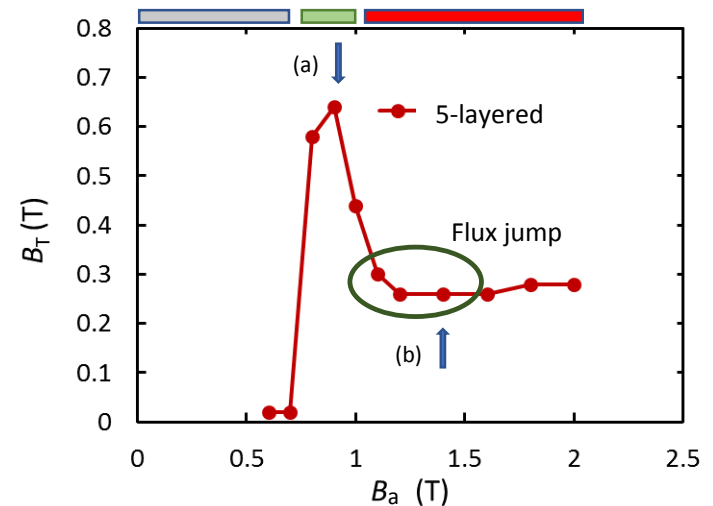


➤  $B_a = 0.9 \text{ T}$   
 Field trapping ratio  
 $(B_T / B_p) \times 100 (\%)$

81%

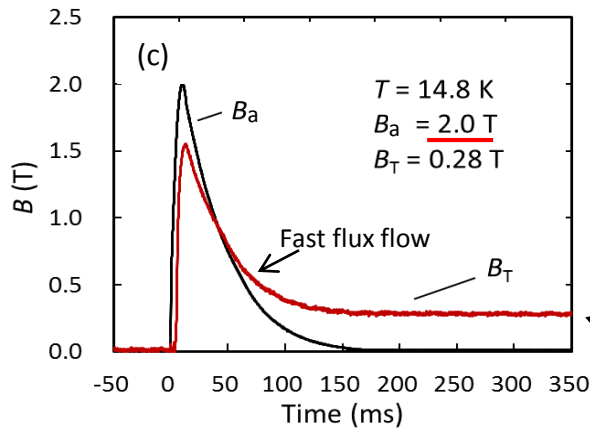


➤  $B_a = 1.4 \text{ T}$   
 Fast flux flow and flux jump at 58 ms lowers the resultant  $B_T$



Large temperature rise causes the flux jump and flow  
 → lower the  $B_T$  values ■  
 → narrow the optimum area of  $B_a$  ■

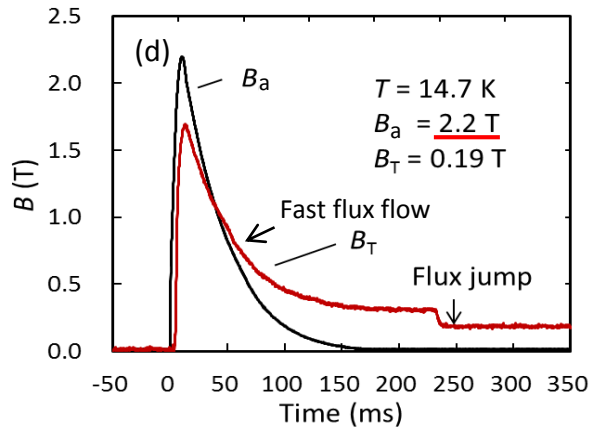
# Field Invasion Profiles (5-layered sample)



➤  $B_a = 2.0 \text{ T}$   
 $(B_T / B_p) \times 100 (\%)$

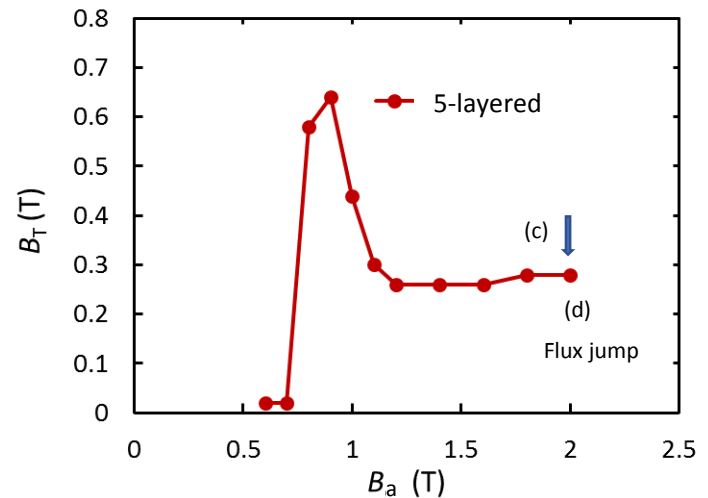
Fast flux flow lowers resultant  $B_T$

18 %



➤  $B_a = 2.2 \text{ T}$

Fast flux flow and sudden flux jump at 234 ms lowers the final  $B_T$  value



Severe heat generation causes fast flux flow and frequent/deep flux jump

## 3 and 5 layered samples

